

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10598529	HAMANAKA, MASAHIKO
	<b>Examiner</b>	<b>Art Unit</b>
	STEPHEN R KOZIOL	2624

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	106, 118	8/10/2010	srk

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
PALM inventor name double patenting search	8/10/2010	srk
EAST text search of above-cited classes for object pose estimation using weighted sharpness differences	8/10/2010	srk
NPL IEEE search for object pose estimation using weighted sharpness differences	8/10/2010	srk
JPO patent and utility model gazette db abstract search for object pose estimation using weighted sharpness differences	8/10/2010	srk

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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